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Semiconductor device package

Abstract

A semiconductor device package includes a substrate and a conductive lid. The conductive lid is disposed within the substrate. The conductive lid defines a waveguide having a cavity. The waveguide is configured to transmit a signal from a first electronic component to a second electronic component through the cavity.

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Background/Summary

CROSS REFERENCE TO RELATED APPLICATION (1) This is a continuation of U.S. patent application Ser. No. 17/010,714, filed Sep. 2, 2020, now U.S. Pat. No. 11,901,270, the content of which is incorporated herein by reference in its entirety.

BACKGROUND

1. Technical Field

(1) The present disclosure relates to a semiconductor device package and a method of manufacturing the same, and more particularly to a semiconductor device package including a waveguide and a method of manufacturing the same.

2. Description of the Related Art

(2) Wireless communication devices, such as cell phones, typically include antennas for transmitting and receiving radio frequency (RF) signals. To reduce signal loss during the transmission, a waveguide may be used. A waveguide is a structure that guides waves, such as electromagnetic waves, with minimal loss of energy by restricting the transmission of energy to one direction.

SUMMARY

(3) In accordance with some embodiments of the present disclosure, a semiconductor device package includes a substrate and a conductive lid. The conductive lid is disposed within the substrate. The conductive lid defines a waveguide having a cavity. The waveguide is configured to transmit a signal from a first electronic component to a second electronic component through the cavity.

Description

BRIEF DESCRIPTION OF THE DRAWINGS

- (1) FIG. 1A illustrates a cross-sectional view of a semiconductor device package, in accordance with some embodiments of the present disclosure.
- (2) FIG. 1B illustrates a side view of the semiconductor device package as shown in FIG. 1A, in accordance with some embodiments of the present disclosure.
- (3) FIG. 1C illustrates an enlarged view of a waveguide of the semiconductor device package as shown in FIG. 1B, in accordance with some embodiments of the present disclosure.
- (4) FIG. 1D illustrates a top view of the waveguide as shown in FIG. 1C, in accordance with some embodiments of the present disclosure.
- (5) FIG. 2A illustrates a cross-sectional view of a semiconductor device package, in accordance with some embodiments of the present disclosure.
- (6) FIG. 2B illustrates a side view of the semiconductor device package as shown in FIG. 2A, in accordance with some embodiments of the present disclosure.
- (7) FIG. 3 illustrates a cross-sectional view of a semiconductor device package, in accordance with some embodiments of the present disclosure.
- (8) FIG. 4 illustrates a cross-sectional view of a semiconductor device package, in accordance with some embodiments of the present disclosure.
- (9) FIG. 5A illustrates a perspective view of a semiconductor device package, in accordance with

some embodiments of the present disclosure.

(10) FIG. 5B illustrates a cross-sectional view of the semiconductor device package as shown in FIG. 5A, in accordance with some embodiments of the present disclosure.

(11) Common reference numerals are used throughout the drawings and the detailed description to indicate the same or similar components. The present disclosure will be readily understood from the following detailed description taken in conjunction with the accompanying drawings.

DETAILED DESCRIPTION

(12) FIG. 1A illustrates a cross-sectional view of a semiconductor device package **1**, in accordance with some embodiments of the present disclosure. FIG. 1B illustrates a side view of the semiconductor device package **1** from a direction D1 as shown in FIG. 1A, in accordance with some embodiments of the present disclosure. FIG. 1C illustrates an enlarged view of a waveguide **12** as shown in FIG. 1B, in accordance with some embodiments of the present disclosure. FIG. 1D illustrates a top view of the waveguide **12** as shown in FIG. 1C, in accordance with some embodiments of the present disclosure. The semiconductor device package **1** includes a substrate **10**, a conductive lid **11**, a waveguide **12**, electronic components **13a**, **13b** and electrical contacts **14**.

(13) The substrate **10** (e.g., a circuit layer or a build-up layer) includes one or more interconnection layers (e.g., conductive layers **10c1**, **10c2**) and one or more dielectric layers (e.g., dielectric layers **10d1**, **10d2**, **10d3**, **10d4**). In some embodiments, the conductive layers **10c1** and **10c2** may include patterned conductive layer, such as redistribution layers (RDL). The conductive layer **10c1** is disposed on a surface **10d11** of the dielectric layer **10d1** and covered by the dielectric layer **10d2**. The conductive layer **10c2** is disposed on a surface **10d12** of the dielectric layer **10d1** and covered by the dielectric layer **10d4**.

(14) In some embodiments, each of the dielectric layers **10d1**, **10d2**, **10d3** and **10d4** may include an organic material, a solder mask, a polyimide (PI), an epoxy, an Ajinomoto build-up film (ABF), one or more molding compounds, one or more pre-impregnated composite fibers (e.g., a pre-preg fiber), a borophosphosilicate glass (BPSG), a silicon oxide, a silicon nitride, a silicon oxynitride, an undoped silicate glass (USG), any combination thereof, or the like. Examples of molding compounds may include, but are not limited to, an epoxy resin including fillers dispersed therein. Examples of a pre-preg fiber may include, but are not limited to, a multi-layer structure formed by stacking or laminating one or more pre-impregnated materials or sheets. In some embodiments, each of the dielectric layers **10d1**, **10d2**, **10d3** and **10d4** may include an inorganic material, such as silicon, a ceramic or the like. Each of the conductive layers **10c1** and **10c2** may be or include a conductive material such as a metal or metal alloy. Examples of the conductive material include gold (Au), silver (Ag), copper (Cu), platinum (Pt), Palladium (Pd), other metal(s) or alloy(s), or a combination of two or more thereof. In some embodiments, there may be any number of conductive layers or dielectric layers depending on design specifications.

(15) The conductive lid **11** (e.g., a metal lid or a leadframe) is disposed within the substrate **10**. For example, the conductive lid **11** is encapsulated or covered by the dielectric layer **10d1** of the substrate **10**. For example, the conductive lid **11** is embedded within the dielectric layer **10d1** of the substrate **10**. In some embodiments, the conductive lid **11** may include Au, Ag, Cu, Pt, Pd, other metal(s) or alloy(s), or a combination of two or more thereof.

(16) As shown in FIG. 1A, the conductive lid **11** may include a base portion **11a** and an extending portion **11b** extending upwardly from the base portion **11a**. The extending portion **11b** is disposed at the edges of the base portion **11a**. As shown in FIG. 1B, the extending portion **11b** is disposed along the edges of the base portion **11a**. For example, the extending portion **11b** may function as a sidewall of the base portion. For example, the extending portion **11b** and the base portion **11a** may define a recess or a space.

(17) The conductive layer **10c1** (e.g., the patterned conductive layer, such as a redistribution layer, RDL) is disposed on a surface **10d11** of the dielectric layer **10d1** and electrically connected to the extending portion **11b** of the conductive lid **11** through the conductive via **10v3**. For example, the

conductive via **10v3** partially penetrates the dielectric layer **10d1** and is electrically connected to the extending portion **11b** of the conductive lid **11**. The conductive via **10v3** is in contact with the extending portion **11b** of the conductive lid **11**. As shown in FIG. **1B**, a plurality of conductive vias **10v3** electrically connect the conductive layer **10c1** with the extending portion **11b** of the conductive lid **11**, and the conductive vias **10v3** may be spaced apart from each other. For example, there is a gap between two adjacent conductive vias **10v3**. For example, from the side view of the waveguide **12** as shown in FIG. **1B**, there are a plurality of openings or holes on the sidewall of the waveguide **12**. The conductive layer **10c1**, the conductive vias **10v3** and the conductive lid **11** may define a cavity **S1** (or a space). In some embodiments, the cavity **S1** is filled with the dielectric layer **10d1**.

(18) As shown in FIG. **1A**, FIG. **1B**, FIG. **1C** and FIG. **1D**, the waveguide **12** may be defined by the conductive lid **11**, the conductive layer **10c1** and the conductive vias **10v3**. The waveguide **12** is configured to guide the signal (e.g., electromagnetic waves) along a direction **D2** (i.e., the direction substantially perpendicular to the direction **D1**) as shown in FIG. **1B**. The waveguide **12** is configured to transmit the signal from a terminal of the waveguide **12** to an opposite terminal of the waveguide **12**. For example, as shown in FIG. **1B** and FIG. **1D**, a conductive layer **10s1** of the substrate **10** electrically connected to and in contact with the waveguide **12** can function as a terminal of the waveguide **12**, and a conductive layer **10s2** of the substrate **10** electrically connected to and in contact with the waveguide **12** can function as an opposite terminal of the waveguide **12**. In some embodiments, the conductive layer **10s1** of the substrate **10** is in contact with the conductive layer **10c1** of the waveguide **12**, and the conductive layer **10s2** of the substrate **10** is in contact with the conductive layer **10c1** of the waveguide **12**. In other embodiments, the conductive layer **10s1** and/or the conductive layer **10s2** may be in contact with the conductive lid **11** (e.g., the extending portion **11b**). The signal may be transmitted from one terminal (i.e., the conductive layer **10s1**) to an opposite terminal (i.e., the conductive layer **10s2**). In some embodiments, the conductive layers **10s1** and **10s2** may function as a microstrip line.

(19) In some embodiments, since the waveguide **12** can guide or direct the electromagnetic waves by restricting the transmission of energy to one direction (e.g., along the direction **D2** as shown in FIG. **1B**), the waveguide **12** can have a minimal loss of energy of the signal. In some embodiments, the power (or a distribution of an electric field) of the signal at one terminal of the waveguide **12** is substantially the same as the power (or a distribution of an electric field) of the signal transmitted to an opposite terminal of the waveguide **12**. In some embodiments, the size (or dimension) of the opening at one terminal of the waveguide **12** is substantially the same as that at an opposite terminal of the waveguide **12**.

(20) As shown in FIG. **1A** and FIG. **1B**, the electronic components **13a** and **13b** are disposed on the surface **101** of the substrate **10** and electrically connected to the substrate **10**. In some embodiments, each of the electrical components **13a** and **13c** may be an active component, such as an integrated circuit (IC) chip or a die. The electronic component **13b** may be a passive electrical component, such as a capacitor, a resistor or an inductor. The electronic components **13a**, **13b** and **13c** can be electrically connected to the substrate **10** by way of flip-chip or wire-bond techniques. In some embodiments, the semiconductor device package **1** may further include a package body (e.g., a molding compound, not shown in the drawings) to cover the electronic components **13a**, **13b** and **13c**.

(21) In some embodiments, since the waveguide **12** can achieve a low signal loss transmission (compared with the conductive lines **12c1**, **12c2**), the waveguide **12** may be used for signal (especially for high-frequency signal) transmission between the electronic components **13a**, **13b** and **13c**. For example, as shown in FIG. **1B**, the signal transmission between the electronic components **13a** and **13c** can be achieved by the waveguide **12**. For example, the waveguide **12** can be configured to transmit signal from a place to another place (e.g., from the electronic component **13a** to the electronic component **13c**) in a package or in a module. In some embodiments, the

electrical components **13a** and **13c** may include a high-frequency circuit, such as an oscillator, an amplifier, a mixer, a modulator, a filter or the like. In some embodiments, one of the electrical components **13a** and **13c** may be replaced by an antenna (or a feeding line of an antenna).

(22) The electronic component **13a** is electrically connected to one terminal (e.g., the conductive layer **10s1**) of the waveguide **12** (e.g., to the conductive layer **10c1**) through the interconnection layer (e.g., through the conductive vias **10v1**, **10v2** and the conductive layer **10c3** as shown in FIG. **1B**) of the substrate **10**. Similarly, the electronic component **13c** is electrically connected to an opposite terminal (e.g., the conductive layer **10s2**) of the waveguide **12** (e.g., to the conductive layer **10cl**) through the interconnection layer of the substrate **10**. The signal (e.g., electromagnetic waves) can be transmitted between the electronic components **13a** and **13c** through the cavity **S1** of the waveguide **12**.

(23) The electrical contacts **14** (e.g. solder balls) are disposed on the surface **102** of the substrate **10** and can provide electrical connections between the semiconductor package device **1** and external components (e.g. external circuits or circuit boards). In some embodiments, the electrical contacts **14** may include controlled collapse chip connection (C4) bumps, ball grid arrays (BGA) or land grid arrays (LGA).

(24) In some embodiments, the waveguide **12** may be formed by the following operations: (i) providing the conductive lid **11**; (ii) forming the dielectric layer **10d1** covering the conductive lid **11** and within the cavity **S1** by, for example, lamination or other suitable techniques; (iii) forming the conductive vias **10v3** penetrating the dielectric layer **10d1** to be in contact with the extending portion **11b** of the conductive lid **11**; and (iv) forming the conductive layer **10c1** on the dielectric layer **11** and in contact with the conductive vias **10v3**.

(25) FIG. **2A** illustrates a cross-sectional view of a semiconductor device package **2**, in accordance with some embodiments of the present disclosure. FIG. **2B** illustrates a side view of the semiconductor device package **2** from a direction **D2** as shown in FIG. **2A**, in accordance with some embodiments of the present disclosure. The semiconductor device package **2** as illustrated in FIG. **2A** and FIG. **2B** is similar to the semiconductor device package **1** as illustrated in FIG. **1A** and FIG. **1B**, and the differences therebetween are described below.

(26) The waveguide **12** of the semiconductor device package **1** is defined by the conductive layer **10c1**, the conductive vias **10v3** and the conductive lid **11**, while the waveguide **22** of the semiconductor device package **2** is defined by a metal layer **22m** (e.g., a metal plate or a metal film) and the conductive lid **11**. For example, the waveguide **22** may be formed by connecting the metal layer **22m** on the extending portion **11b** of the conductive lid **11**. For example, the metal layer **22m** is in contact with the extending portion **11b** of the conductive lid **11**. As shown in FIG. **2A**, the metal layer **22m** and the conductive lid **11** define a cavity **S2** (or a space). In some embodiments, the dielectric layer **10d1** is not disposed within the cavity **S2**. For example, the cavity **S2** may be an air cavity. Since the air has a dielectric constant (**Dk**) less than the **Dk** of a dielectric material, the waveguide **22** can have a better performance for data transmission (especially for high-frequency signal).

(27) As shown in FIG. **2B**, unlike the conductive vias **10v3** as shown in FIG. **1B** spaced apart from each other, the metal layer **22m** may be an entire metal plate (or metal film), and thus there is no opening or hole on the sidewall of the waveguide **22**. In some embodiments, the conductive layers **10s1** and **10s2** may be electrically connected to and in contact with two opposite lateral surfaces of the metal layer **22m**. Alternatively, the conductive layers **10s1** and **10s2** may be electrically connected to and in contact with a top surface of the metal layer **22m**.

(28) In some embodiments, the waveguide **22** may be formed by the following operations: (i) providing the conductive lid **11**; (ii) connecting the metal layer **22m** on the extending portion **11b** of the conductive lid **11**; and (iii) forming the dielectric layer **10d1** covering the conductive lid **11** and the metal layer **22m** by, for example, lamination or other suitable techniques.

(29) FIG. **3** illustrates a cross-sectional view of a semiconductor device package **3**, in accordance

with some embodiments of the present disclosure. The semiconductor device package **3** is similar to the semiconductor device package **1** as shown in FIG. **1B**, and the differences therebetween are described below.

(30) The semiconductor device package **3** includes a waveguide **32**. The waveguide **32** is similar to the waveguide **12** as shown in FIG. **1B**, except that the waveguide **32** includes a plurality of slots **32s1**, **32s2** on a sidewall of the extending portion **11b** of the conductive lid **11**. Each of the first set of slots **32s1** is inclined in a first direction. Each of the second set of slots **32s2** is inclined in a second direction. In some embodiments, the first direction is different from the second direction. For example, the first direction is not parallel to the second direction. In some embodiments, the waveguide **32** may also function as a slot antenna. The waveguide **32** may be configured to transmit or receive electromagnetic waves substantially perpendicular to the sidewall of the waveguide **32**. In some embodiments, the slots **32s1** and **32s2** are disposed at or adjacent to the sidewall of the waveguide. For example, the slots **32s1** and **32s2** may be exposed from the dielectric layer **10d1** of the substrate **10**, and thus the radiation emitted from the slots **32s1** and **32s2** would not be affected by the substrate **10**.

(31) FIG. **4** illustrates a cross-sectional view of a semiconductor device package **4**, in accordance with some embodiments of the present disclosure. The semiconductor device package **4** is similar to the semiconductor device package **2** as shown in FIG. **2B**, and the differences therebetween are described below.

(32) The semiconductor device package **4** includes a waveguide **42**. The waveguide **42** is similar to the waveguide **22** as shown in FIG. **2B**, except that the waveguide **42** includes a plurality of slots **42s1**, **42s2** on a sidewall of the extending portion **11b** of the conductive lid **11**. Each of the first set of slots **42s1** is inclined in a first direction. Each of the second set of slots **42s2** is inclined in a second direction. In some embodiments, the first direction is different from the second direction. For example, the first direction is not parallel to the second direction. In some embodiments, the waveguide **42** may also function as a slot antenna. The waveguide **42** may be configured to transmit or receive electromagnetic waves substantially perpendicular to the sidewall of the waveguide **42**.

(33) FIG. **5A** illustrates a perspective view of a semiconductor device package **5**, in accordance with some embodiments of the present disclosure. FIG. **5B** illustrates a cross-sectional view of the semiconductor device package **5** as shown in FIG. **5A**, in accordance with some embodiments of the present disclosure. The semiconductor device package **5** includes a substrate **50**, a conductive lid **51**, an antenna **52**, electronic components **13a**, **13b** and electrical contacts **14**.

(34) The substrate **50** (e.g., a circuit layer or a build-up layer) includes one or more interconnection layers (e.g., conductive layers **50c**) and one or more dielectric layers **50d**. In some embodiments, the conductive layers **50c** may include patterned conductive layer, such as a RDL. A portion of the conductive layers **50c** is covered by the dielectric layer **50d** while the rest portion of the conductive layers **50c** may be exposed from the dielectric layer **50d** for electrical connections. The conductive layers **50c** disposed on different layers of the dielectric layers **50d** can be electrically connected through a conductive via **50v**.

(35) In some embodiments, each of the dielectric layers **50d** may include an organic material, a solder mask, a PI, an epoxy, an ABF, one or more molding compounds, one or more pre-impregnated composite fibers (e.g., a pre-preg fiber), a BPSG (BPSG), a silicon oxide, a silicon nitride, a silicon oxynitride, an USG, any combination thereof, or the like. Examples of molding compounds may include, but are not limited to, an epoxy resin including fillers dispersed therein. Examples of a pre-preg fiber may include, but are not limited to, a multi-layer structure formed by stacking or laminating one or more pre-impregnated materials or sheets. In some embodiments, each of the dielectric layers **50d** may include an inorganic material, such as silicon, a ceramic or the like. Each of the conductive layers **50c** may be or include a conductive material such as a metal or metal alloy. Examples of the conductive material include Au, Ag, Cu, Pt, Pd, other metal(s) or

alloy(s), or a combination of two or more thereof. In some embodiments, there may be any number of conductive layers or dielectric layers depending on design specifications.

(36) The electronic components **13a** and **13b** are disposed on the substrate **50** and electrically connected to the substrate **50**. The electrical contacts **14** are disposed on the substrate **50** and electrically connected to the substrate **50** to provide electrical connections between the semiconductor device package **5** and external components (e.g. external circuits or circuit boards). In some embodiments, the electronic components **13a**, **13b** and the electrical contacts **14** are the same or similar to the electronic components **13a**, **13b** and the electrical contacts **14** as illustrated in FIG. **1A** and FIG. **1B**.

(37) The conductive lid **51** (e.g., a metal lid or a leadframe) is disposed on a surface **502** of the substrate **50** opposite to the surface **501** on which the electronic components **13a** and **13b** are disposed. In some embodiments, the conductive lid **51** can be connected to the surface **502** of the substrate **50** through an adhesive layer. The substrate **50** may include a feeding element (not shown) electrically connected to the conductive via **50v**, and the conductive lid **51** may include an opening (not shown) corresponding to the feeding element. The signal (e.g., RF signal) can be transmitted from the feeding element to the cavity **52s** through the opening of the conductive lid **51**, and then radiated to the outside through the slots **52h**. In some embodiments, the conductive lid **51** may include Au, Ag, Cu, Pt, Pd, other metal(s) or alloy(s), or a combination of two or more thereof.

(38) As shown in FIG. **5B**, the conductive lid **51** (e.g., a metal lid or a leadframe) may include a base portion **51a** and an extending portion **51b** extending from the base portion **51a**. The base portion **51a** is in contact with the substrate **50** and electrically connected to the substrate **50**. The extending portion **51b** is disposed at the edges of the base portion **51a**. A metal layer **52m** (e.g., a metal plate or a metal film) is disposed on the extending portion **51b** of the conductive lid **51**. The metal layer **52m** and the conductive lid **51** may define a cavity **52s** (or a space). The metal layer **52m** include a plurality of slots **52h** to expose the cavity **52s**.

(39) In some embodiments, the metal layer **52m** and the conductive lid **51** may define the antenna **52** (e.g., a slot antenna). The antenna **52** is configured to transmit or receive electromagnetic waves in a direction substantially perpendicular to the surface of the substrate **50** on which the conductive lid **51** is disposed.

(40) As used herein, the terms “substantially,” “substantial,” “approximately,” and “about” are used to denote and account for small variations. For example, when used in conjunction with a numerical value, the terms can refer to a range of variation of less than or equal to $\pm 10\%$ of that numerical value, such as less than or equal to $\pm 5\%$, less than or equal to $\pm 4\%$, less than or equal to $\pm 3\%$, less than or equal to $\pm 2\%$, less than or equal to $\pm 1\%$, less than or equal to $\pm 0.5\%$, less than or equal to $\pm 0.1\%$, or less than or equal to $\pm 0.05\%$. As another example, a thickness of a film or a layer being “substantially uniform” can refer to a standard deviation of less than or equal to $\pm 10\%$ of an average thickness of the film or the layer, such as less than or equal to $\pm 5\%$, less than or equal to $\pm 4\%$, less than or equal to $\pm 3\%$, less than or equal to $\pm 2\%$, less than or equal to $\pm 1\%$, less than or equal to $\pm 0.5\%$, less than or equal to $\pm 0.1\%$, or less than or equal to $\pm 0.05\%$. The term “substantially coplanar” can refer to two surfaces within micrometers of lying along a same plane, such as within $40\text{ }\mu\text{m}$, within $30\text{ }\mu\text{m}$, within $20\text{ }\mu\text{m}$, within $10\text{ }\mu\text{m}$, or within $1\text{ }\mu\text{m}$ of lying along the same plane. Two surfaces or components can be deemed to be “substantially perpendicular” if an angle therebetween is, for example, $90^\circ \pm 10^\circ$, such as $\pm 5^\circ$, $\pm 4^\circ$, $\pm 3^\circ$, $\pm 2^\circ$, $\pm 1^\circ$, $\pm 0.5^\circ$, $\pm 0.1^\circ$, or $\pm 0.05^\circ$. When used in conjunction with an event or circumstance, the terms “substantially,” “substantial,” “approximately,” and “about” can refer to instances in which the event or circumstance occurs precisely, as well as instances in which the event or circumstance occurs to a close approximation.

(41) As used herein, the singular terms “a,” “an,” and “the” may include plural referents unless the context clearly dictates otherwise. In the description of some embodiments, a component provided

“on” or “over” another component can encompass cases where the former component is directly on (e.g., in physical contact with) the latter component, as well as cases where one or more intervening components are located between the former component and the latter component.

(42) As used herein, the terms “conductive,” “electrically conductive” and “electrical conductivity” refer to an ability to transport an electric current. Electrically conductive materials typically indicate those materials that exhibit little or no opposition to the flow of an electric current. One measure of electrical conductivity is Siemens per meter (S/m). Typically, an electrically conductive material is one having a conductivity greater than approximately $10^{4.4}$ S/m, such as at least $10^{4.5}$ S/m or at least $10^{4.6}$ S/m. The electrical conductivity of a material can sometimes vary with temperature. Unless otherwise specified, the electrical conductivity of a material is measured at room temperature.

(43) Additionally, amounts, ratios, and other numerical values are sometimes presented herein in a range format. It can be understood that such range formats are used for convenience and brevity, and should be understood flexibly to include not only numerical values explicitly specified as limits of a range, but also all individual numerical values or sub-ranges encompassed within that range as if each numerical value and sub-range is explicitly specified.

(44) While the present disclosure has been described and illustrated with reference to specific embodiments thereof, these descriptions and illustrations do not limit the present disclosure. It can be clearly understood by those skilled in the art that various changes may be made, and equivalent elements may be substituted within the embodiments without departing from the true spirit and scope of the present disclosure as defined by the appended claims. The illustrations may not necessarily be drawn to scale. There may be distinctions between the artistic renditions in the present disclosure and the actual apparatus, due to variables in manufacturing processes and such. There may be other embodiments of the present disclosure which are not specifically illustrated. The specification and drawings are to be regarded as illustrative rather than restrictive.

Modifications may be made to adapt a particular situation, material, composition of matter, method, or process to the objective, spirit and scope of the present disclosure. All such modifications are intended to be within the scope of the claims appended hereto. While the methods disclosed herein have been described with reference to particular operations performed in a particular order, it can be understood that these operations may be combined, sub-divided, or re-ordered to form an equivalent method without departing from the teachings of the present disclosure. Therefore, unless specifically indicated herein, the order and grouping of the operations are not limitations of the present disclosure.

Claims

1. A semiconductor device package, comprising: a conductive structure including a base portion and an extending portion extending upwardly from the base portion, wherein the conductive structure defines a waveguide having a cavity; a dielectric layer encapsulating the conductive structure; and a first conductive via partially penetrating the dielectric layer and connecting a bottom surface of the base portion of the conductive structure.
2. The semiconductor device package of claim 1, wherein the dielectric layer is partially disposed within the cavity and contacts the extending portion of the conductive structure.
3. The semiconductor device package of claim 1, further comprising: an electronic component; and an antenna, wherein the waveguide is configured to transmit a signal provided by the electronic component to the antenna.
4. The semiconductor device package of claim 1, wherein the conductive structure has a first edge and a second edge opposite to the first edge, and the dielectric layer extends continuously over the first edge and the second edge.
5. The semiconductor device package of claim 1, further comprising: a second conductive via

partially penetrating the dielectric layer and connecting a top surface of the extending portion of the conductive structure.

6. The semiconductor device package of claim 5, wherein the second conductive via and the first conductive via are tapered toward each other.

7. The semiconductor device package of claim 5, wherein the extending portion of the conductive structure vertically overlapped with the second conductive via and the first conductive via.

8. A semiconductor device package, comprising: a conductive structure including a base portion and a first extending portion served as a first sidewall of the base portion, wherein the base portion and the first extending portion collectively define a waveguide; an antenna disposed over the conductive structure and electrically connected with the waveguide; an electronic component disposed over the conductive structure and electrically connected with the waveguide, wherein the waveguide is configured to transmit a signal provided by the electronic component to the antenna along a signal transmitting direction; and conductive vias contacting the first extending portion and arranged along the signal transmitting direction.

9. The semiconductor device package of claim 8, wherein the conductive vias are spaced at substantially equal intervals, and the conductive lid includes a second extending portion opposite to the first extending portion and extending upwardly from the base portion, wherein the second extending portion serves as a second sidewall of the base portion.

10. The semiconductor device package of claim 9, further comprising: a conductive layer connecting the first sidewall to the second sidewall, wherein the conductive layer connects the first sidewall through a conductive via tapering toward the first sidewall.

11. The semiconductor device package of claim 10, wherein the conductive layer, the first sidewall, the second sidewall, and the base portion collectively define the waveguide.

12. A semiconductor device package, comprising: a conductive structure defining a waveguide having a cavity; a dielectric layer partially disposed within the cavity; a circuit structure disposed under the conductive structure, wherein the circuit structure includes a conductive via and a feeding element configured to transmit a signal to the cavity through the conductive via; and an electronic component disposed under the circuit structure, wherein the dielectric layer and the electronic component are disposed at different elevations with respect to the conductive structure.

13. The semiconductor device package of claim 12, further comprising: a conductive layer disposed over the cavity and including a plurality of slots, wherein the signal is configured to be radiated through at least one of the plurality of slots.

14. The semiconductor device package of claim 12, wherein the waveguide includes a plurality of cavities separated from one another and the dielectric layer is exposed through the plurality of cavities.

15. The semiconductor device package of claim 14, wherein the waveguide includes a plurality of slots arranged in a plurality of rows, and each of the plurality of rows includes a slot array.

16. The semiconductor device package of claim 15, wherein each of the plurality of rows corresponds to one of the plurality of cavities.

17. The semiconductor device package of claim 12, further comprising: a plurality of electrical contacts disposed under the circuit structure and configured to connect an external device to the circuit structure, and wherein the plurality of electrical contacts are vertically overlapped with the conductive structure.

18. The semiconductor device package of claim 12, further comprising: a conductive via tapering from the electronic component to the top surface of the conductive structure.

19. The semiconductor device package of claim 12, further comprising: a passive component disposed under the circuit structure, wherein the electronic component comprises an active component.

20. The semiconductor device package of claim 12, wherein a central line of the electronic component is misaligned with a central line of the cavity in a cross-sectional view.

